

1,048,576 WORD X 18 BIT DYNAMIC RAM

DESCRIPTION

The TC5118180AJ/FT is the new generation dynamic RAM organized 1,048,576 word by 18 bit. The TC5118180AJ/AFT utilizes Toshiba's CMOS silicon gate process technology as well as advanced circuit techniques to provide wide operating margins, both internally and to the system user. Multiplexed address inputs permit the TC5118180AJ/AFT to be packaged in a standard 40 pin plastic SOJ, and 50/44 pin plastic TSOP. The package size provides high system bit densities and is compatible with widely available automated testing and insertion equipment. System oriented features include single power supply of $5V \pm 10\%$ tolerance, direct interfacing capability with high performance logic families such as Schottky TTL,

FEATURES

- 1,048,576 word by 4 bit organization
- Fast access time and cycle time
- Single power supply of $5V \pm 10\%$ with a built-in V_{BB} generator
- Low Power
 - 825mW MAX. Operating (TC5118180AJ/AFT-70)
 - 715mW Max. Operating TC5118180AJ/AFT-80
 - 5.5mW Max. Standby
- Outputs unlatched at cycle end allows two-dimensional chip selection
- Read-Modify-Write, \overline{CAS} before \overline{RAS} refresh, \overline{RAS} -only refresh, Hidden refresh, Fast Page Moode capability
- All inputs and outputs TTL compatible
- 1024 refresh cycles/16ms
- Package TC5118180AJ : SOJ42-P-400
TC5118180AFT : TSOP50-P-400

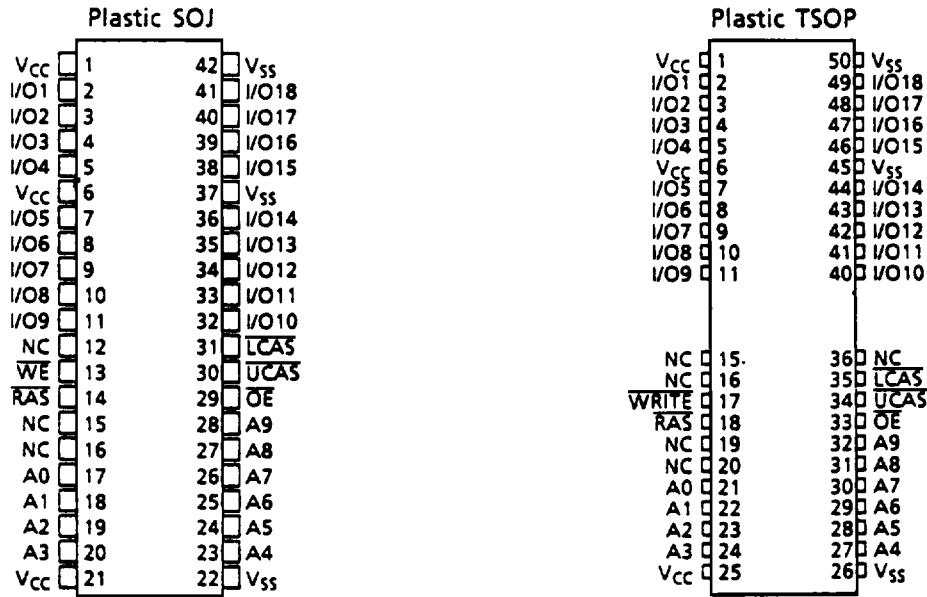
KEY PARAMETERS

ITEM	TC5118180AJ/AFT	
	-70	-80
t_{RAC} \overline{RAS} Access Time	70ns	80ns
t_{AA} Column Address Access Time	35ns	40ns
t_{CAC} \overline{CAS} Access Time	20ns	20ns
t_{RC} Cycle Time	130ns	150ns
t_{PC} Fast Page Mode Cycle Time	45ns	50ns

PIN NAME

A0~A9	Row Address Strobe
RAS	Row Address Strobe
UCAS	Upper Byte Control
LCAS	Lower Byte Control
WRITE	Read/Write Input
OE	Output Enable
I/O1~I/O18	Data Input/Output
V _{CC}	Power (+ 5V)
V _{SS}	Ground
N.C.	No Connection

PIN CONNECTION (TOP VIEW)



RECOMMENDED D.C. OPERATING CONDITION (Ta = 0~70°C)

SYMBOL	PARAMETER	MIN.	TYP	MAX	UNIT	NOTE
V _{CC}	Supply Voltage	4.5	5.0	5.5	V	2
V _{IH}	High Level Input Voltage	2.4	-	V _{CC} +0.5*	V	2
V _{IL}	Low Level Input Voltage	-0.5**	-	0.8	V	2

* V_{CC} + 2.0V at pulse width ≤ 20ns. (pulse width is measured at V_{CC})

** -2.0V at pulse width ≤ 20ns. (pulse width is measured at 0V)

D.C. OPERATING CHARACTERISTICS (V_{CC} = 5V ± 10%, Ta = 0~70°C)

SYMBOL	PARAMETER		MIN.	MAX.	UNIT	NOTE
I _{CC1}	OPERATING CURRENT	TC5118180AJ/AFT-70	-	150	mA	3, 4 5
	Average Power Supply Operating Current (RAS, UCAS, LCAS Addrs. Cycling: t _{RC} = t _{RC} MIN)	TC5118180AJ/AFT-80	-	130		
I _{CC2}	STANDBY CURRENT			2	mA	
	Power Supply Standby Current (RAS = UCAS = LCAS = V _{IH})					
I _{CC3}	RAS ONLY REFRESH CURRENT	TC5118180AJ/AFT-70	-	150	mA	3, 5
	Average Power Supply Current (RAS Only Mode (RAS, Cycling, UCAS, = LCAS V _{IH} ; t _{RC} = t _{RC} MIN)	TC5118180AJ/AFT-80	-	130		
I _{CC4}	FAST PAGE MODE CURRENT	TC5118180AJ/AFT-70	-	85	mA	3, 4, 5
	Average Power Supply Current, Fast Page Mode (RAS = V _{IL} , UCAS, LCAS Addrs. Cycling: t _{PC} = t _{PC} MIN)	TC5118180AJ/AFT-80	-	75		
I _{CC5}	STANDBY CURRENT Power Supply Standby Current, (RAS = UCAS = LCAS = V _{CC} - 0.2V)		-	1	mA	
I _{CC6}	CAS BEFORE RAS REFRESH CURRENT	TC5118180AJ/AFT-70	-	150	mA	3, 5
	Average Power Supply Current, CAS Before RAS Mode (RAS, UCAS, LCAS, Cycling: t _{RC} = t _{RC})	TC5118180AJ/AFT-80	-	130		
I _{I(L)}	INPUT LEAKAGE CURRENT Input Leakage Current, any input (0V ≤ V _{IN} ≤ V _{CC} , All Other Pins Not Under Test = OV)		-10	10	μA	
I _{O(L)}	OUTPUT LEAKAGE CURRENT (D _{OUT} is disabled, 0V ≤ V _{OUT} ≤ V _{CC})		-10	10	μA	
V _{OH}	OUTPUT LEVEL (Output "H" Level Voltage (I _{OUT} = 5mA))		2.4	-	V	
V _{OL}	OUTPUT LEVEL (Output "H" Level Voltage (I _{OUT} = 4.2mA))		-	0.4	V	

CAPACITANCE *(T_{CC} = 5V ± 10%, f = 1MHz, Ta = 0~70°C)

SYMBOL	PARAMETER	MIN	MAX	UNIT
C _{I1}	Input Capacitance (A0 ~A9)	-	5	pF
C _{I2}	Input Capacitance (RAS, UCAS, LCAS, WRITE, OE)	-	7	pF
C _O	Input/Output Capacitance (I/O1~I/O18)	-	7	pF

ELECTRICAL CHARACTERISTICS AND RECOMMENDED A.C. OPERATING CONDITIONS
($V_{CC} = 5V \pm 10\%$, $T_a = 0 \sim 70^\circ\text{C}$)(Notes 6,7,8)

SYMBOL	PARAMETER	TC5118180AJ/AFT				UNIT	NOTES
		-70		-80			
		MIN	MAX.	MIN	MAX		
t _{RC}	Random Read or Write Cycle Time	130	-	150	-	ns	
t _{RMW}	Read-Modify-Write Cycle	185	-	205	-	ns	
t _{PC}	Fast Page Mode Cycle Time	45	-	50	-	ns	
t _{PRMW}	Fast Page Mode Read-Modify-Write Cycle Time	100	-	105	-	ns	
t _{RAC}	Access Time from RAS	-	70	-	80	ns	9,14,15
t _{CAC}	Access Time from CAS	-	20	-	20	ns	9,14
t _{AA}	Access Time from Column Address	-	35	-	40	ns	9,15
t _{CPA}	Access Time from CAS Precharge	-	40	-	45	-	9
t _{CLZ}	CAS to Output in Low-Z	0	-	0	-	ns	9
t _{OFF}	Output Buffer Turn-off Delay	0	15	0	15	ns	10
t _T	Transition Time (Rise and Fall)	3	50	3	50	ns	8
t _{RP}	RAS Presharge Time	50	-	60	-	ns	
t _{RAS}	RAS Pulse Width	70	10,000	80	10,000	ns	
t _{RASP}	RAS Pulse Width (Fast Page Mode)	70	100,000	80	100,000	ns	
t _{RSH}	RAS Hold Time	20	-	20	-	ns	
t _{RHCP}	RAS Hold Time From CAS Precharge (Fast Page Mode)	40	-	45	-	ns	
t _{CSH}	CAS Hold Time	70	-	80	-	ns	
t _{CAS}	CAS Pulse Width	20	10,000	20	10,000	ns	
t _{RCD}	RAS to CAS Delay Time	20	50	20	60	ns	14
t _{RAD}	RAS to Column Address Delay Time	15	35	15	40	ns	15
t _{CRP}	CAS to RAS Precharge Time	5	-	5		ns	
t _{CP}	CAS Precharge Time	10	-	10	-	ns	
t _{ASR}	Row Address Set-Up Time	0	-	0	-	ns	
t _{RAH}	Row Address Hold Time	10	-	10	-	ns	
t _{ASC}	Column Address Set-Up Time	0	-	0	-	ns	
t _{CAH}	Column Address Hold Time	10	-	15	-	ns	
t _{RAL}	Column Address To RAS Lead Time	35	-	40	-	ns	
t _{RCS}	Read Command Set-Up Time	0	-	0	-	ns	
t _{RCH}	Read Command Hold Time	0	-	0	-	ns	11
t _{RRH}	Read Command Hold Time referenced to RAS	0	-	0	-	ns	11
t _{WCH}	Write Command Hold Time	15	-	15	-	ns	

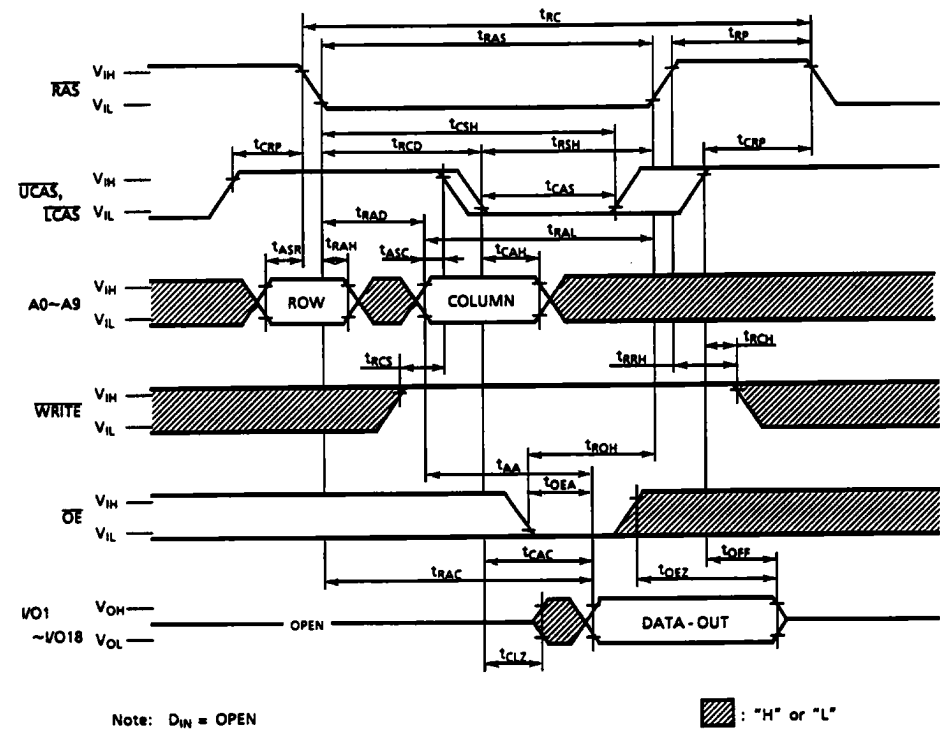
ELECTRICAL CHARACTERISTICS AND RECOMMENDED A.C. OPERATING CONDITIONS (CONT)

SYMBOL	PARAMETER	TC5118180AJ/AFT				UNIT	NOTES
		-70		-80			
		MIN	MAX	MIN	MAX		
t _{WP}	Write Command Pulse Width	15	-	15	-	ns	
t _{RWL}	Write Command to \overline{RAS} Lead Time	20	-	20	-	ns	
t _{CWL}	Write Command to \overline{CAS} Lead Time	20	-	20	-	ns	
t _{DS}	Data Set-Up Time	0	-	0	-	ns	12
t _{DH}	Data Hold Time	15	-	15	-	ns	12
t _{REF}	Refresh Period	-	8	-	8	ns	
t _{WCS}	Write Command Set-Up Time	0	-	0	-	ns	13
t _{CWD}	\overline{CAS} to \overline{WRITE} Delay Time	50	-	50	-	ns	13
t _{RWD}	\overline{RAS} to \overline{WRITE} Delay Time	100	-	110	-	ns	13
t _{AWD}	Column Address to \overline{WE} Delay Time	65	-	70	-	ns	13
t _{CPWD}	\overline{CAS} Precharge to \overline{WRITE} Delay Time	70	-	75	-	ns	13
t _{CSR}	\overline{CAS} Set-Up Time (\overline{CAS} before \overline{RAS} Cycle)	5	-	5	-	ns	
t _{CHR}	\overline{CAS} Hold Time (\overline{CAS} before \overline{RAS} Cycle)	15	-	15	-	ns	
t _{RPC}	\overline{RAS} to \overline{CAS} Precharge Time	5	-	5	-	ns	
t _{CPT}	\overline{CAS} Precharge Time (\overline{CAS} before \overline{RAS} Counter Test Cycle)	30	-	30	-	ns	
t _{ROH}	\overline{RAS} Hold Time referenced to OE	10	-	10		ns	
t _{OEA}	\overline{OE} Access Time	-	20	0	20	ns	9
t _{OED}	\overline{OE} to Data Delay	20	-	20	-	ns	
t _{OEZ}	Output buffer turn off Delay Time from \overline{OE}	0	20	0	20	ns	10
t _{OEH}	\overline{OE} Command Hold Time	20	-	20	-	ns	
t _{ODS}	Output Disable Set-Up Time	0	-	0	-	ns	

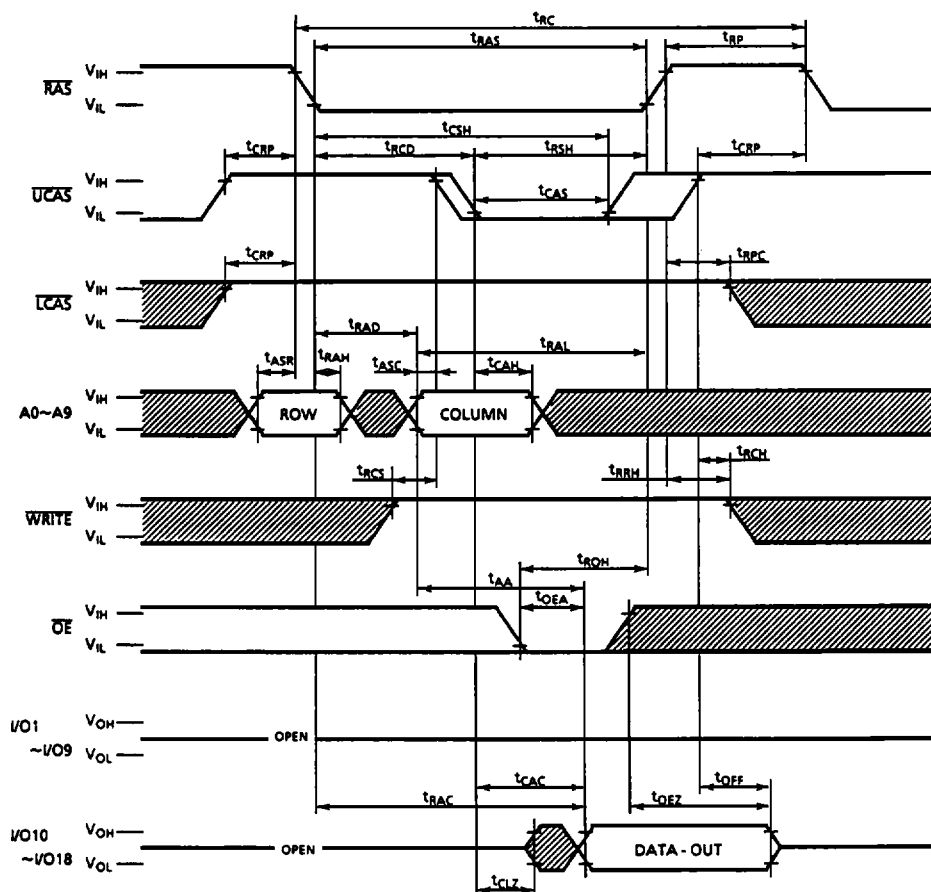
NOTES:

1. Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device.
2. All voltages are referenced to V_{SS} .
3. I_{CC1} , I_{CC3} , I_{CC4} , I_{CC6} depend on cycle rate.
4. I_{CC1} , I_{CC4} depend on output loading. Specified values are obtained with the output open.
5. Address can be changed one or less while $\overline{RAS}=V_{IL}$. In case of I_{CC4} , it can be changed once or less during a fast page mode cycle (t_{PC}).
6. An initial pause of 200 μ s is required after power-up followed by 8 \overline{RAS} only refresh cycles before proper device operation is achieved. In case of using internal refresh counter, a minimum of 8 \overline{CAS} before \overline{RAS} refresh cycles instead of 8 \overline{RAS} only refresh cycles are required.
7. AC measurements assume $t_1=5$ ns.
8. V_{IH} (min.) and V_{IL} (max.) are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL} .
9. Measured with a load equivalent to 2 TTL loads and 100pF.
10. t_{OFF} (max.) and t_{OEZ} (max.) define the time at which the output achieves the open circuit condition and are not referenced to output voltage levels.
11. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
12. These parameters are referenced to \overline{UCAS} or \overline{LCAS} leading edge in early write cycles and to \overline{WRITE} leading edge in Read-Modify-Write cycles.
13. t_{WCS} , t_{RWD} , t_{CWD} , t_{AWD} and t_{CPWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS} \geq t_{WCS}(\text{min.})$, the cycle is an early write cycle and the data output will remain open circuit (high impedance) through the entire cycle; If $t_{RWD} \geq t_{RWD}(\text{min.})$, $t_{CWD} \geq t_{CWD}(\text{min.})$, $t_{AWD} \geq t_{AWD}(\text{min.})$ and $t_{CPWD} \geq t_{CPWD}(\text{min.})$, (Fast Page Mode), the cycle is a Read-Modify-Write cycle and the data out will contain data read from the selected cell; If neither of the above sets of condition is satisfied, the condition of the data out (at access time) is indeterminate.
14. Operation within the $t_{RCD}(\text{max.})$ limit insures that t_{RAC} can be met. $t_{RCD}(\text{max.})$ is specified as a reference point only: If t_{RCD} is greater than the specified $t_{RCD}(\text{max.})$ limit, then access time is controlled by t_{CAC} .
15. Operation within the $t_{RAD}(\text{max.})$ limit insures that $t_{RAC}(\text{max.})$ can be met. $t_{RAD}(\text{max.})$ is specified as a reference point only: If t_{RAD} is greater than the specified $t_{RAD}(\text{max.})$ limit, then access time is controlled by t_{AA} .

READ CYCLE



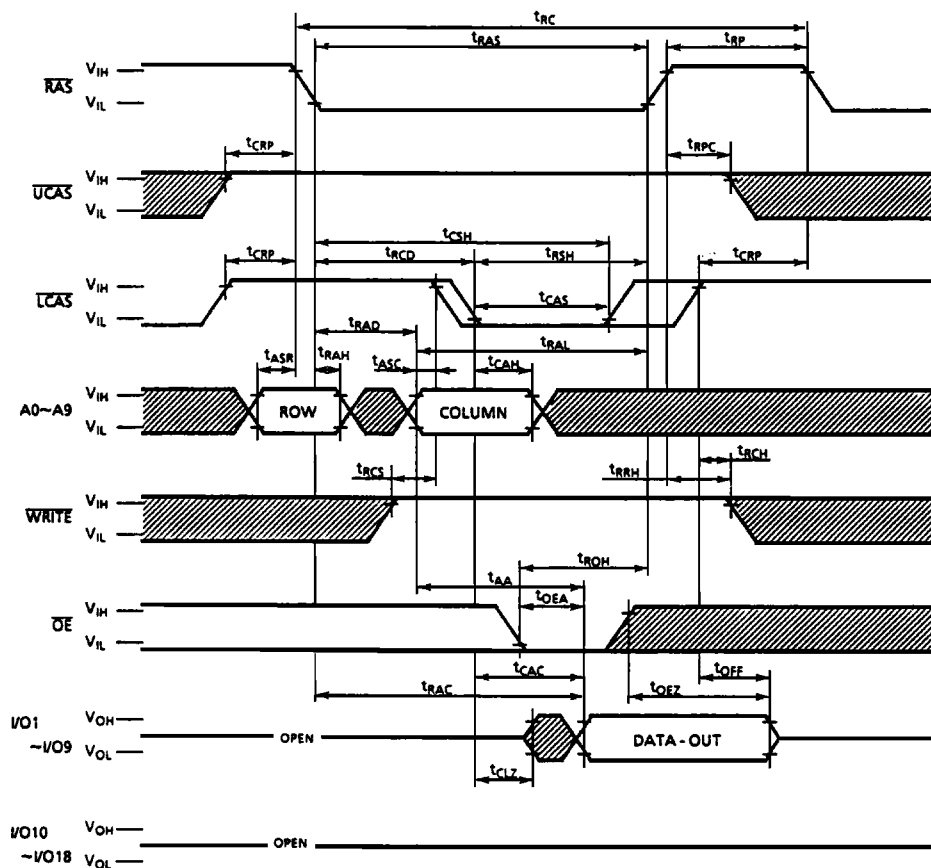
UPPER BYTE READ CYCLE



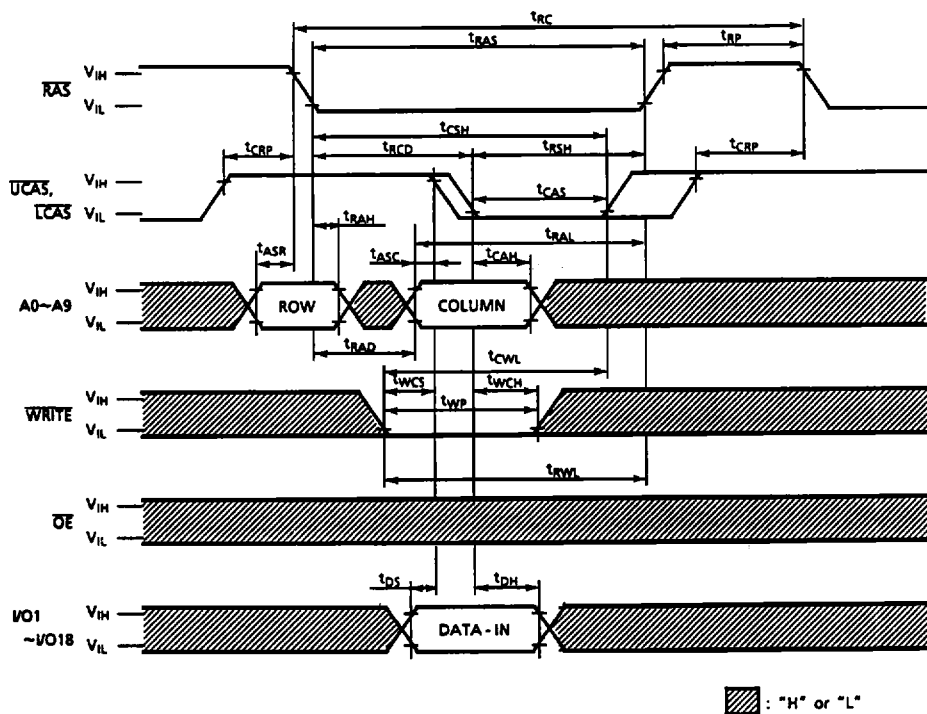
Note: $D_{IN}(I/O1 \sim I/O9) = \text{Don't Care}$
 $D_{IN}(I/O10 \sim I/O18) = \text{OPEN}$

■ : "H" or "L"

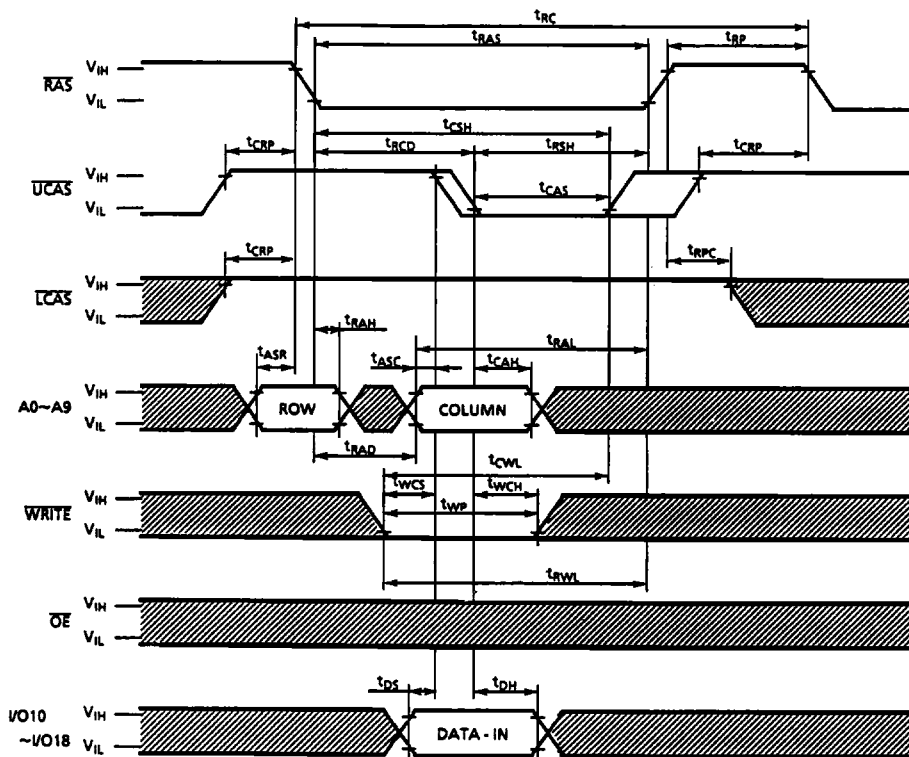
LOWER BYTE READ CYCLE



Note: $D_{IN}(I/O1 \sim I/O9) = \text{OPEN}$
 $D_{IN}(I/O10 \sim I/O18) = \text{Don't Care}$

WRITE CYCLE (EARLY WRITE)Note: D_{OUT} = OPEN

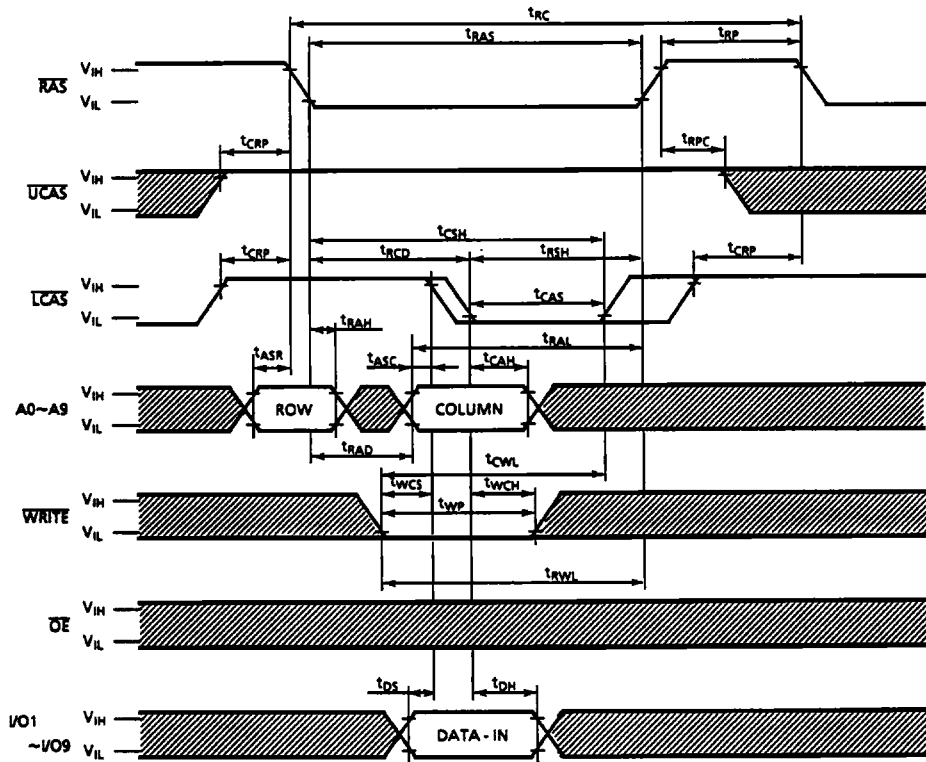
UPPER BYTE WRITE CYCLE (EARLY WRITE)



■ : "H" or "L"

Note: D_{IN} (I/O1~I/O9) = Don't Care
 D_{OUT} = OPEN

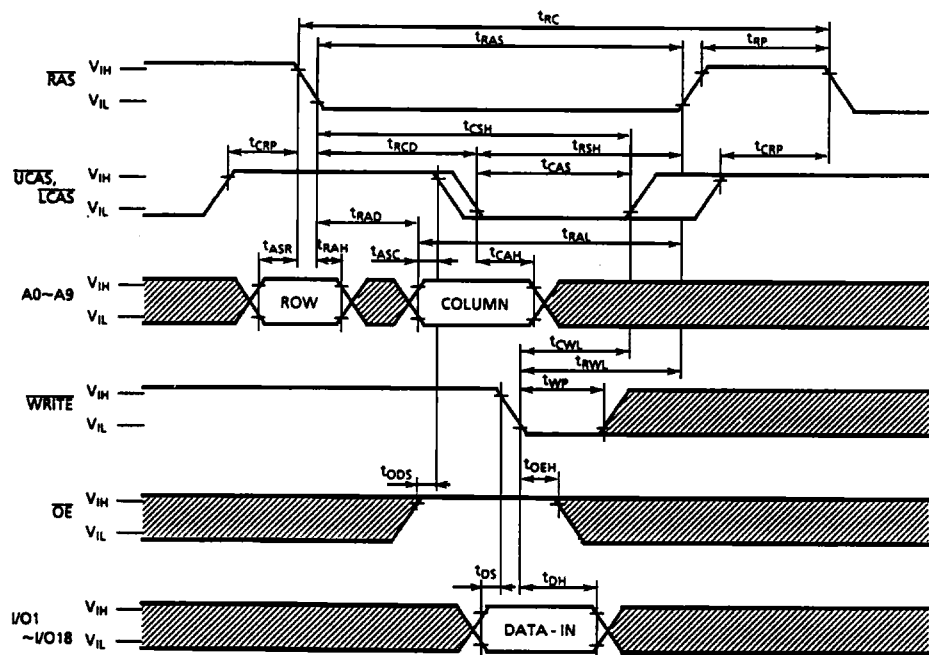
LOWER BYTE WRITE CYCLE (EARLY WRITE)



▨ : "H" or "L"

Note: D_{IN} (I/O10~I/O18) = Don't Care
 D_{OUT} = OPEN

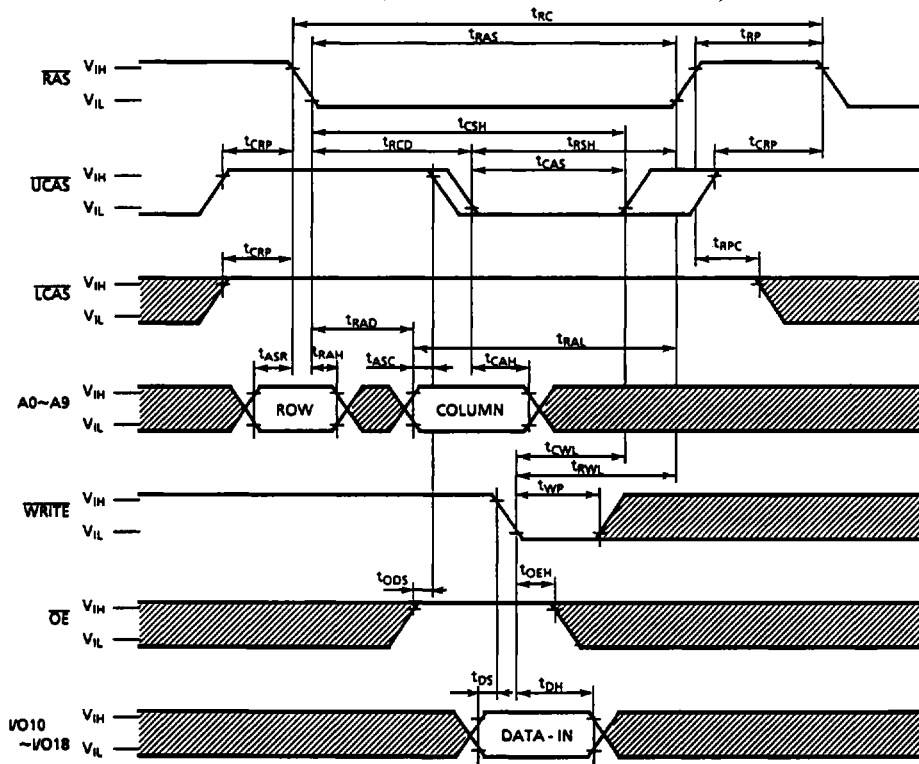
WRITE CYCLE (OE CONTROLLED WRITE)



Note: DOUT = OPEN

■ : "H" or "L"

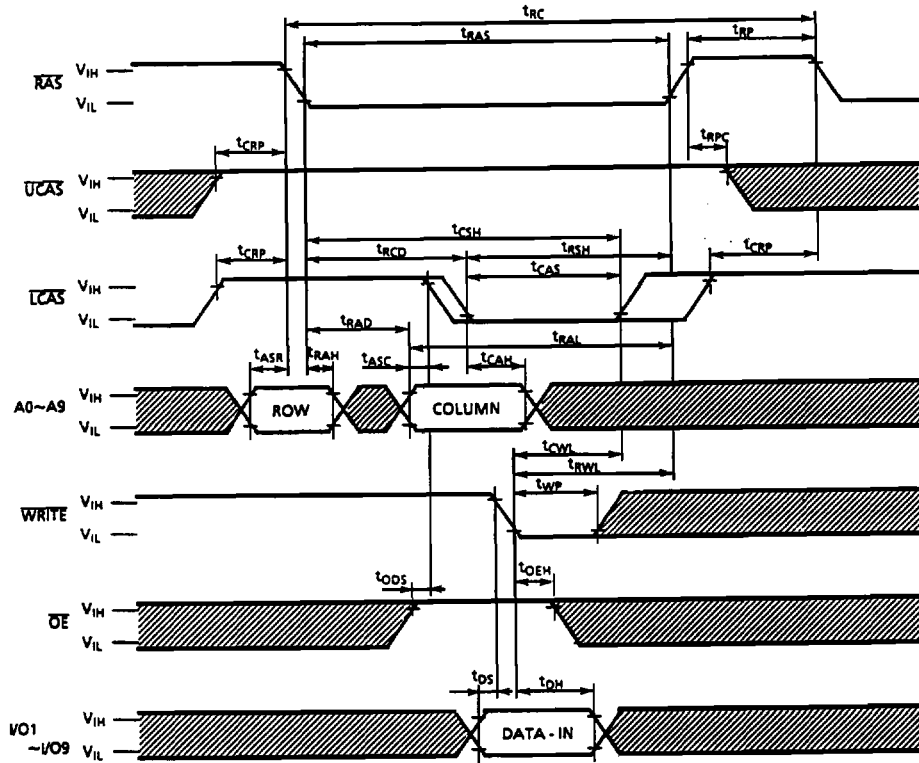
UPPER BYTE WRITE CYCLE (OE CONTROLLED WRITE)



Note: D_{IN} (I/O1-I/O9) = Don't Care
 D_{OUT} = OPEN

▨ : "H" or "L"

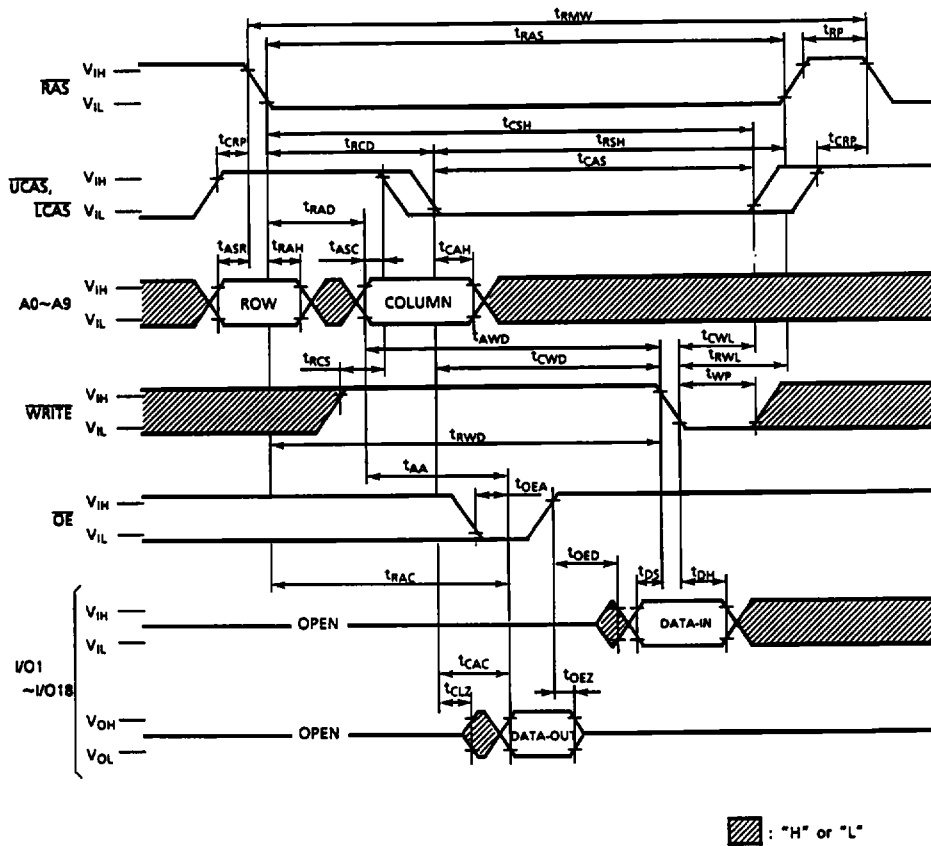
LOWER BYTE WRITE CYCLE (OE CONTROLLED WRITE)

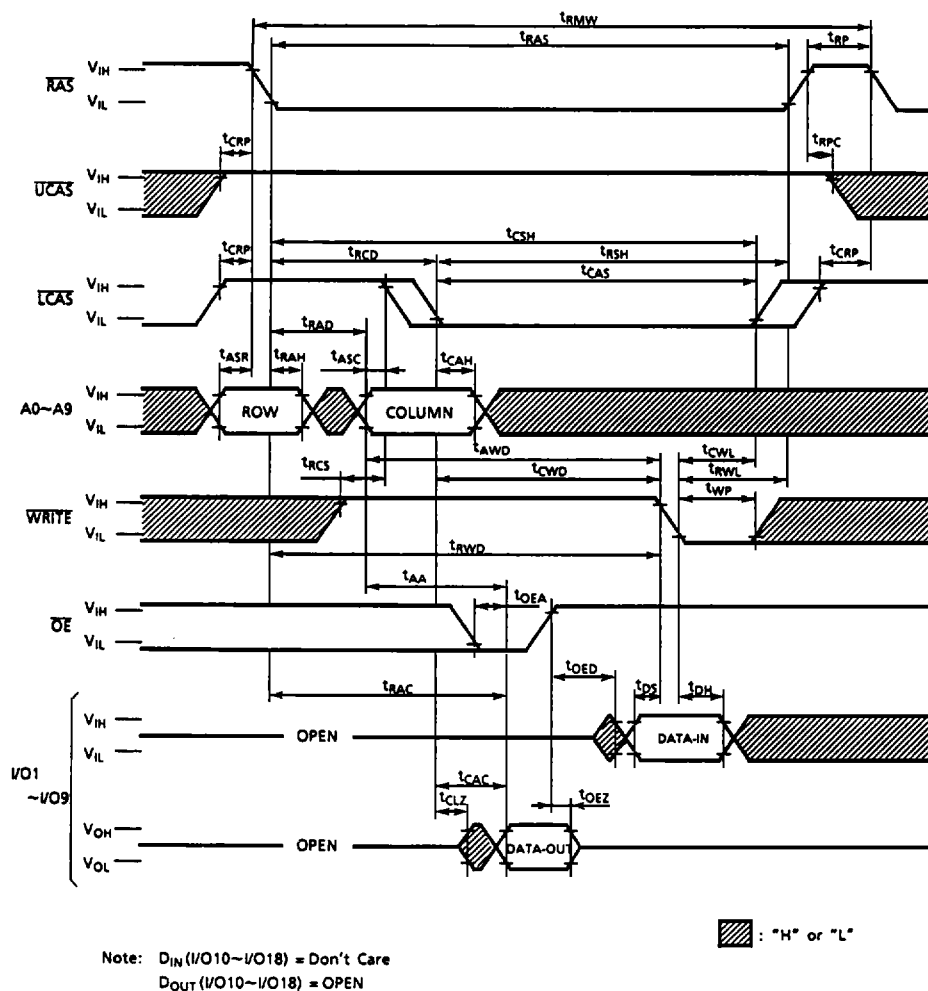


Note: D_{IN} (I/O10-I/O18) = Don't Care
 D_{OUT} = OPEN

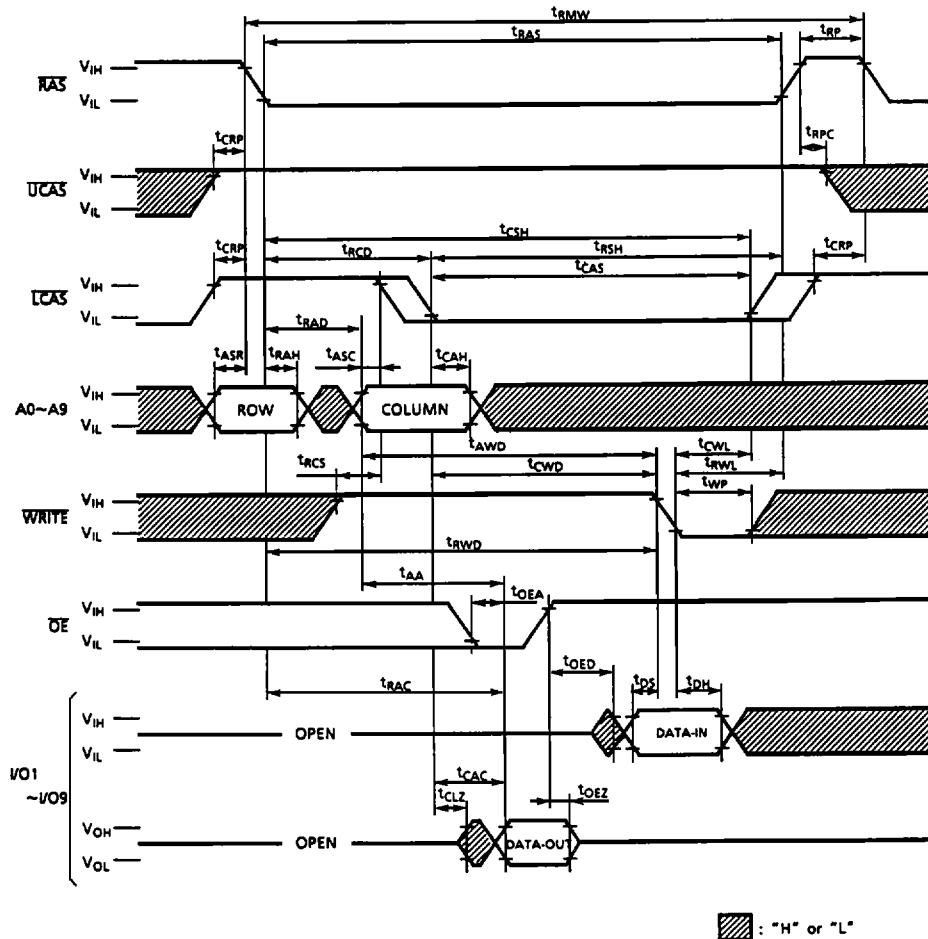
■ : "H" or "L"

READ-MODIFY-WRITE CYCLE



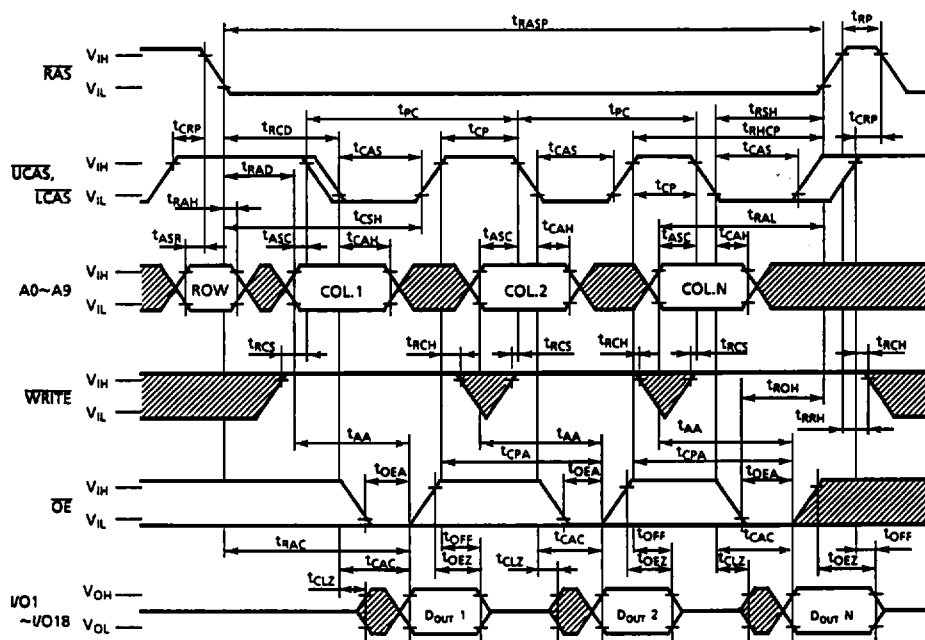


LOWER BYTE READ-MODIFY-WRITE CYCLE




Note: $D_{IN}(I/O10 \sim I/O18) = \text{Don't Care}$
 $D_{OUT}(I/O10 \sim I/O18) = \text{OPEN}$

Figure 1: A single neuron



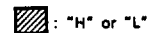
Note: $D_{IN} = OPEN$

: "H" or "L"

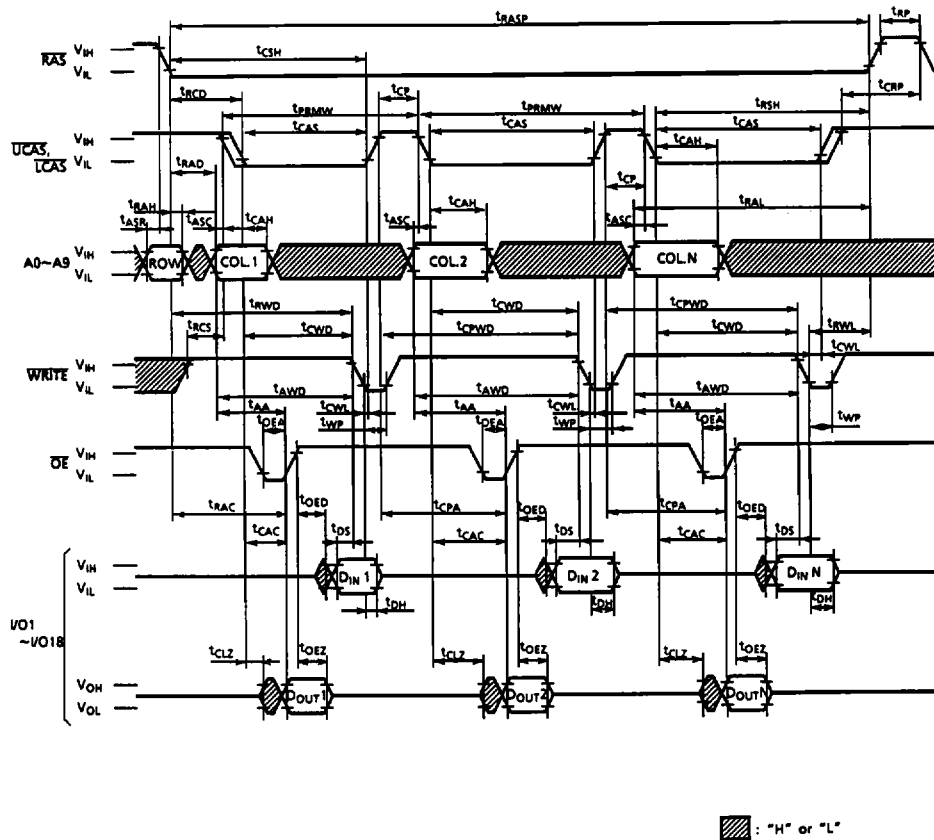
t_{RASP}



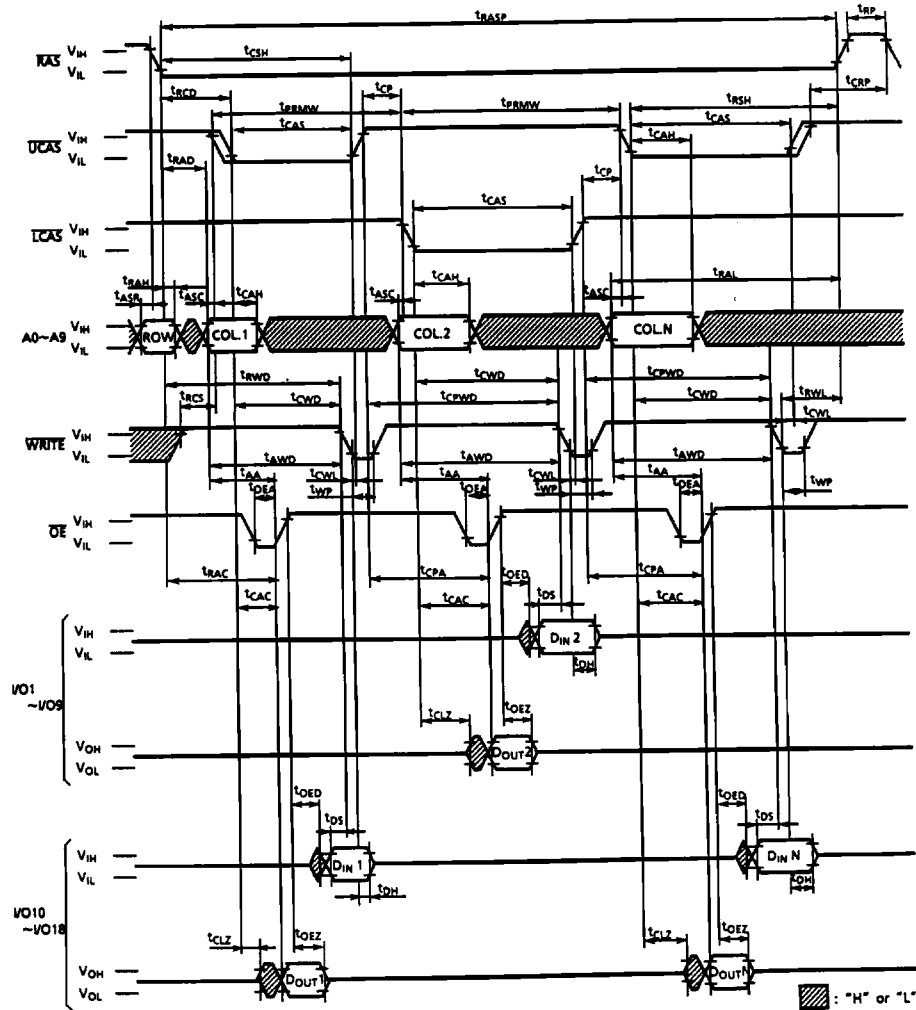
: "H" or "L"



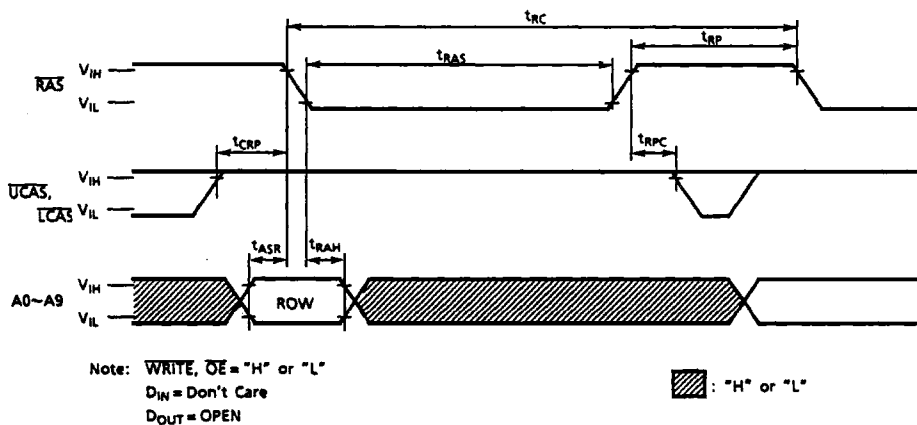
FAST PAGE MODE READ-MODIFY-WRITE CYCLE



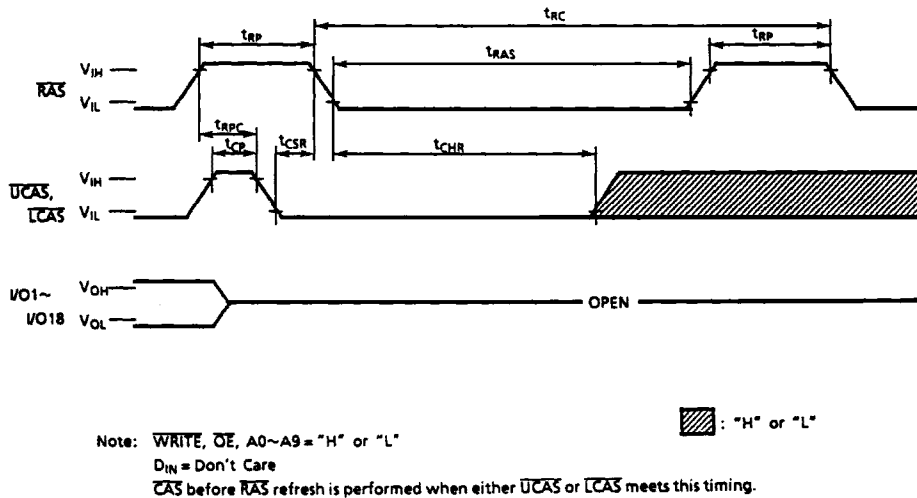
FAST PAGE MODE BYTE READ-MODIFY-WRITE CYCLE

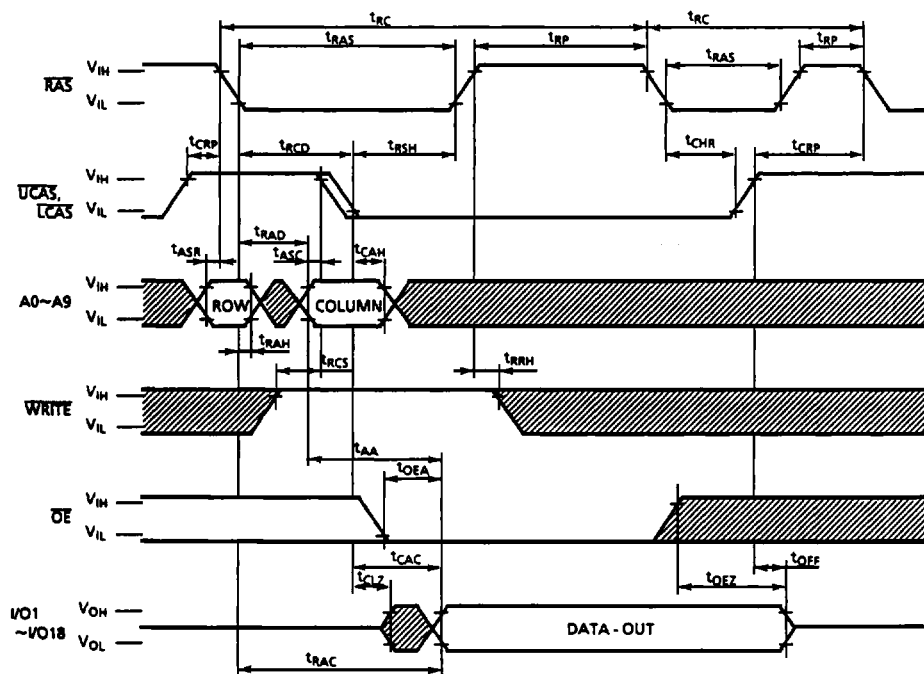


RAS ONLY REFRESH CYCLE



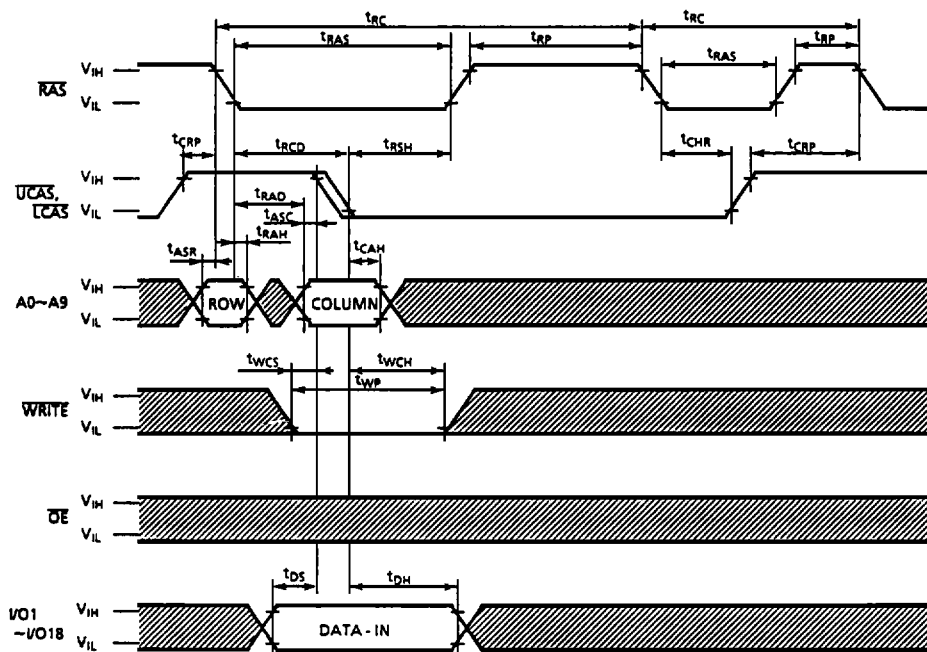
CAS BEFORE RAS ONLY REFRESH CYCLE



HIDDEN REFRESH CYCLE (READ)Note: D_{IN} = OPEN

: "H" or "L"

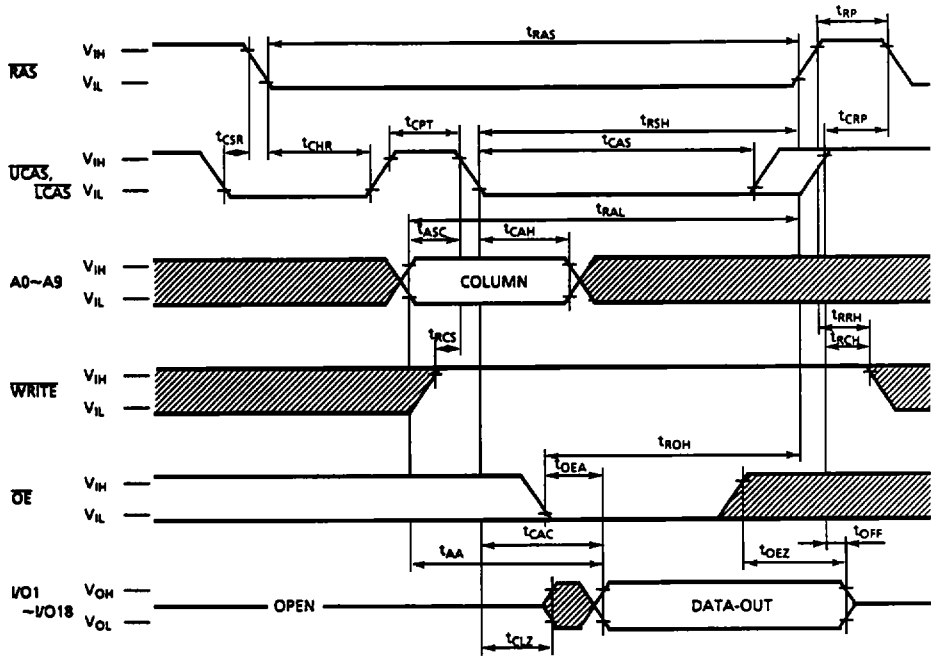
HIDDEN REFRESH CYCLE (WRITE)



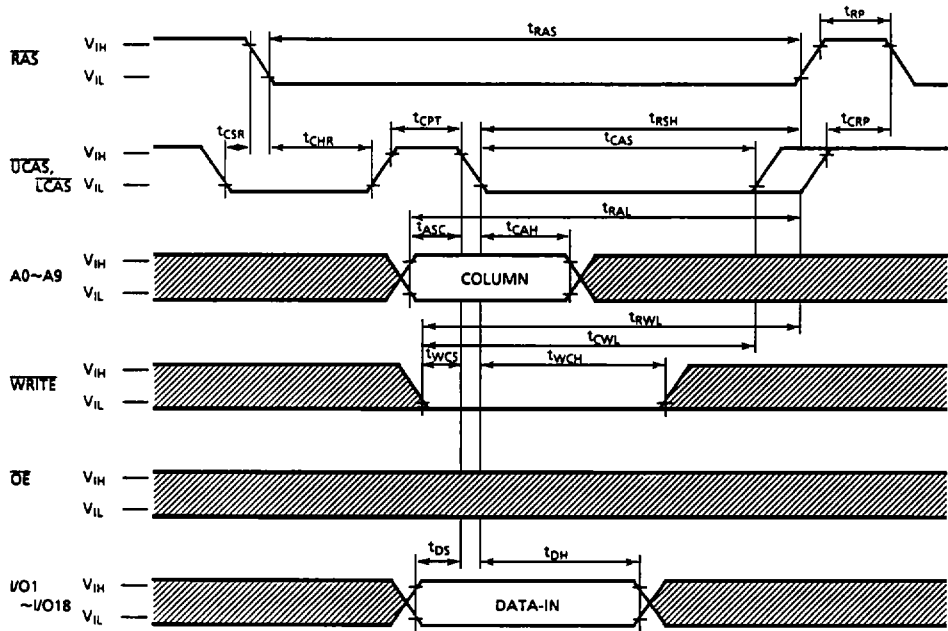
Note: D_{OUT} = OPEN

▨ : "H" or "L"

CAS BEFORE RAS REFRESH COUNTER TEST READ CYCLE



CAS BEFORE RAS REFRESH COUNTER TEST WRITE CYCLE



Note: D_{OUT} = OPEN

▨ : "H" or "L"

CAS BEFORE RAS REFRESH COUNTER TEST READ-MODIFY-WRITE CYCLE

